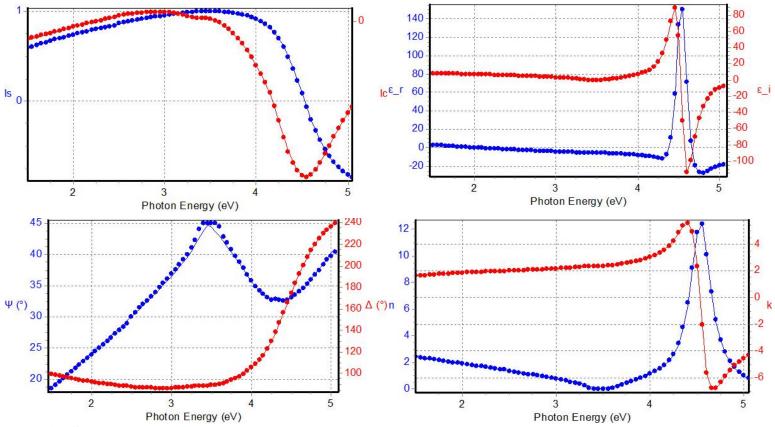
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Supplementary Information:

Fig. S1. Comparison between acquired ellipsomtery data (data points) and the classical dispersion model fit (solid line) used for oxide layer thickness measurements (for case 900° C).